L Number	Hits	Search Text	DB	Time stamp
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2	0	10/655850	USPAT; US-PGPUB	2004/10/31 11:34
-	444	702/82-84.ccls.	USPAT; US-PGPUB	2004/10/31 10:47
-	469	700/109,110.ccls.	USPAT; US-PGPUB	2004/10/30 09:29
-	833	702/82-84.ccls. or 700/109,110.ccls.	USPAT; US-PGPUB	2004/10/30 09:29
-	926	700/121.ccls. not 700/109,110.ccls.	USPAT; US-PGPUB	2004/10/30 10:13
-	116	(700/121.ccls. not 700/109,110.ccls.) and (determin$3 same yield)	USPAT; US-PGPUB	2004/10/30 10:21
-	327	(700/121.ccls. not 700/109,110.ccls.) and yield	USPAT; US-PGPUB	2004/10/30 10:21
-	211	((700/121.ccls. not 700/109,110.ccls.) and yield) not ((700/121.ccls. not 700/109,110.ccls.) and (determin$3 same yield))	USPAT; US-PGPUB	2004/10/30 10:25
-	301	determin$3 with yield with loss	USPAT; US-PGPUB	2004/10/30 10:31
-	35	determin$3 with yield with loss same (semiconductor or wafer)	USPAT; US-PGPUB	2004/10/30 10:31
-	5	"6367040"	USPAT; US-PGPUB	2004/10/30 10:51
-	16	("4801869" | "5355212" | "5438527" | "5598341" | "5754432" | "5761064" | "5777901" | "5787190" | "5822218" | "5828778" | "5940300" | "5943437" | "6016562" | "6017771" | "6061814" | "6169960").PN.	USPAT	2004/10/31 09:00
-	4	("3751647" | "5544256" | "5777901" | "6265232").PN.	USPAT	2004/10/31 09:08
-	192	kill adj2 ratio	USPAT; US-PGPUB	2004/10/31 09:30
-	0	kill adj2 ratio same calibrat$3	USPAT; US-PGPUB	2004/10/31 09:30
-	13	kill adj2 ratio and calibrat$3	USPAT; US-PGPUB	2004/10/31 09:32
-	7	kill adj2 ratio same weight$3	USPAT; US-PGPUB	2004/10/31 10:33
-	0	yield with impact with calibrat$3 with factor	USPAT; US-PGPUB	2004/10/31 11:33
-	14	yield same impact same calibrat$3 same factor	USPAT; US-PGPUB	2004/10/31 10:34
-	142	kill adj2 ratio and weight$3	USPAT; US-PGPUB	2004/10/31 10:42
-	3	yield adj2 loss and calibration adj2 factor	USPAT; US-PGPUB	2004/10/31 10:57
-	139	defect with excursion	USPAT; US-PGPUB	2004/10/31 10:47
-	0	defect with excursion with limit	USPAT; US-PGPUB	2004/10/31 10:47
-	3	defect with excursion same calibrat$3	USPAT; US-PGPUB	2004/10/31 10:51
-	18	defect with calibrat$3 with factor	USPAT; US-PGPUB	2004/10/31 10:52
-	359	yield adj2 loss and calibrat$3	USPAT; US-PGPUB	2004/10/31 10:57

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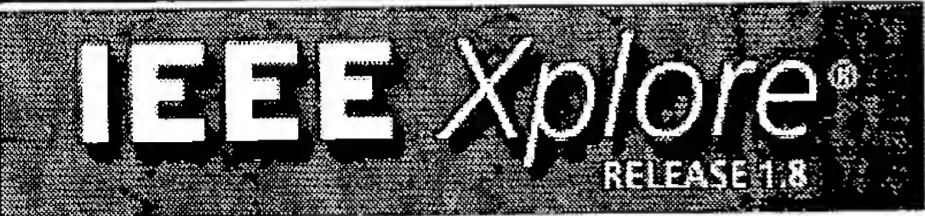
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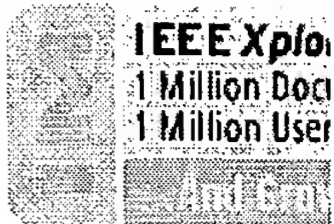☐ Check to search within this result set

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1 **SmartBit™: bitmap to defect correlation software for yield improvement**
Merino, M.A.; Cruceta, S.; Garcia, A.; Recio, M.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2000 IEEE/SEMI , 12-14 Sept. 2000
Pages:194 - 198

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1 **The impact of tolerance on kill ratio estimation for memory**
Patterson, O.D.; Hansen, M.H.;
Semiconductor Manufacturing, IEEE Transactions on , Volume: 15 , Issue: 4 , Nov. 2002
Pages:404 - 410

[Abstract]   [PDF Full-Text (517 KB)]   **IEEE JNL**

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2 **The impact of tolerance on kill ratio estimation for memory**
Patterson, O.D.; Hansen, M.H.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2000 IEEE/SEMI , 12-14 Sept. 2000
Pages:175 - 180

[Abstract]   [PDF Full-Text (488 KB)]   **IEEE CNF**

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3 **Critical area based yield prediction using in-line defect classification information [DRAMs]**
Segal, J.; Sagatelian, A.; Hodgkins, B.; Ben Chu; Singh, T.; Berman, H.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2000 IEEE/SEMI , 12-14 Sept. 2000
Pages:83 - 88

[Abstract]   [PDF Full-Text (508 KB)]   **IEEE CNF**

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4 **Evaluation of the yield impact of epitaxial defects on advanced semiconductor technologies**
Williams, R.; Jacques, R.; Akbulut, M.; Wayne Chen;
Advanced Semiconductor Manufacturing Conference and Workshop, 2000 IEEE/SEMI , 12-14 Sept. 2000
Pages:1 - 7

[Abstract]   [PDF Full-Text (528 KB)]   **IEEE CNF**

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5 SmartBit^{TM}: bitmap to defect correlation software for yield improvement
Merino, M.A.; Cruceta, S.; Garcia, A.; Recio, M.;
Advanced Semiconductor Manufacturing Conference and Workshop, 2000
IEEE/SEMI , 12-14 Sept. 2000
Pages:194 - 198

[Abstract]   [PDF Full-Text (372 KB)]   **IEEE CNF**

6 Key considerations in the development of defect sampling methodologies
McIntyre, M.; Nurani, R.K.; Akella, R.;
Advanced Semiconductor Manufacturing Conference and Workshop, 1996. ASMC
96 Proceedings. IEEE/SEMI 1996 , 12-14 Nov. 1996
Pages:81 - 85

[Abstract]   [PDF Full-Text (484 KB)]   **IEEE CNF**

7 Limitations to estimating yield based on in-line defect measurements
Riley, S.L.;
Defect and Fault Tolerance in VLSI Systems, 1999. DFT '99. International
Symposium on , 1-3 Nov. 1999
Pages:46 - 54

[Abstract]   [PDF Full-Text (132 KB)]   **IEEE CNF**

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